


<p style="text-align: center;">Search Notes</p> 	<p>Application/Control No.</p> <p>10650596</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>DEFRANCESCO ET AL.</p>
	<p>Examiner</p> <p>EDWARD CHANG</p>	<p>Art Unit</p> <p>4143</p>

SEARCHED			
Class	Subclass	Date	Examiner
705	36	11-30-07	EC
705	35	11-30-07	EC

SEARCH NOTES		
Search Notes	Date	Examiner
EAST -- Previous art search	11-30-07	EC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
705	36	11-30-07	EC
705	38	11-30-07	EC